Specialist Applications

Products Available



Additional products offered to enhance the standard product range.

HIGHER ACCURACY ORIENTATIONS / CLEAVED FLATS

Surface orientation can be measured to an accuracy of $\pm 0.02^{\circ}$ using a triple axis X-ray diffractometer system. Substrates can also be supplied with very precise misorientations in any direction from the growth plane - please ask for the orientation you require. We also offer wafers with cleaved flats.

Due to material losses in re-orienting, nonstandard orientations may be subject to minimum order requirements.

NOVEL INDICES

Higher index substrates of the type (x, 1, 1) where x = 1, 2, 3, 4, 5, 6 etc. and orientations such as (110) are available for most materials - please ask for the orientation you require.

Due to material losses in re-orienting, nonstandard orientations may be subject to minimum order requirements.

"PROCESS TRIAL" GRADE WAFERS

Suitable for use as sacrificial test wafers in multi-wafer epitaxy reactors, process monitoring, machine set-up, etching experiments and a variety of other less critical applications. Please ask for specific requirements.

ULTRA THIN WAFERS

Extremely thin (150 µm) Gallium Arsenide (2" and 3") or Indium Phosphide spacer wafers are available for laser facet coating applications.

Wafers of this thickness are not finished to our usual "epi-ready" surface standards -

please ask for more details. **SOUARE WAFERS**

OPTICAL BLANKS

Circular or rectangular blanks for further processing into optical lenses are available in a variety of diameters and thicknesses.

SEED CRYSTALS FOR BULK CRYSTAL GROWTH

Seeds of various dimensions can be supplied with pre-cut grooves ready for use in standard seed chucks - please ask for the size you require.

Non-standard seed sizes may be subject to minimum order requirements.







